

Photoluminescence and Scintillation Properties of Eu:CaHfO₃ Single Crystals

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(Received October 20, 2023; accepted January 23, 2024)

Keywords: scintillator, radiation detector, photoluminescence, CaHfO₃

Eu:CaHfO₃ single crystals with various Eu concentrations were synthesized by the floating zone method, and their photoluminescence (PL) and scintillation properties were investigated. All the samples showed PL peaks at 590, 620, and 650 nm, which were due to the 4f-4f transitions of Eu³⁺. The PL quantum yield of 1.0% Eu:CaHfO₃ was the highest at 42.2% among the samples. The X-ray-induced scintillation spectra showed several emission peaks in the range of 400–690 nm, and the emissions were attributed to the 4f-4f transitions of Eu³⁺. Among the samples, 0.05% Eu:CaHfO₃ showed the highest intensity. In the afterglow curves, the levels were within the range of 1,000–10,000 ppm and those of previous studies.

1. Introduction

Inorganic scintillators can absorb ionizing radiation with high energy to momentarily convert it into photons with low energy.^(1–3) Taking advantage of this feature, the scintillators have been applied to radiation detectors by combining them with photodetectors that can convert the photons into electrical signals.^(4,5) The scintillation detectors are classified into current and photon counting mode measurements depending on their application.^(6,7) In particular, the detectors for the current mode type integrate the signal for a period of milliseconds and have been used in applications such as X-ray computed tomography (CT) and flat panel detectors for X-ray radiography.⁽⁸⁾ The scintillators for the current mode type require properties such as high emission intensity, a large effective atomic number (Z_{eff}), high density (ρ), and low afterglow level (AL). However, since no scintillators satisfy all the required properties, new scintillators have been developed.^(9–14)

HfO₂-based compounds such as RE₂Hf₂O₇ (RE = La, Gd, Lu) and AEHfO₃ (AE = Ca, Sr, Ba) have attracted attention as candidates for scintillators owing to their large Z_{eff} and high ρ . In previous reports on HfO₂-based scintillators, only CaHfO₃ with Z_{eff} (65.2) and ρ (6.95 g/cm³) showed a scintillation light yield above 10,000 photons/MeV.^(15–21) Moreover, our research group has investigated the scintillation properties of CaHfO₃ doped with Ti, Ce, Pr, Tb, and Tm,^(18,21–26)

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<https://doi.org/10.18494/SAM4758>

and CaHfO_3 doped with various rare-earth elements was found to show high luminescence properties.

Eu^{3+} is used as a luminescence center for red scintillators, and the emission wavelength is well matched with a Si-based photodetector. A representative Eu^{3+} -doped material, $\text{Eu}:(\text{Y,Gd})_2\text{O}_3$ ceramic, is used in a commercial scintillator for X-ray CT.^(4,27–29) Furthermore, many Eu^{3+} -doped scintillators have been developed in previous studies.^(30–38) Therefore, it is considered that Eu^{3+} is useful for scintillators. However, the scintillation properties of $\text{Eu}:\text{CaHfO}_3$ have not been reported. In this study, $\text{Eu}:\text{CaHfO}_3$ single crystals were synthesized by the floating zone (FZ) method, and their photoluminescence (PL) and scintillation properties were investigated.

2. Experimental Setup

An FZ furnace with four Xe lamps (Crystal Systems Corporation, FZ-T-12000-X-VPO-PC-YH) was used to synthesize $\text{Eu}:\text{CaHfO}_3$ single crystals.⁽¹⁶⁾ The Eu concentrations were 0.01, 0.05, 0.1, 0.5, and 1.0 at% with respect to Ca. CaO (99.99%, Furuuchi Chemical), HfO_2 (99.95%, Rare Metallic), and Eu_2O_3 (99.99%, Furuuchi Chemical) were used as starting materials and uniformly blended using a mortar and pestle. To account for Ca evaporation during the crystal growth, CaO was raised by 10% in relation to the stoichiometric composition.⁽¹⁸⁾ The mixtures were placed inside balloons to form cylindrical rods by applying hydrostatic pressure. The rods with different Eu concentrations were subsequently calcined at 1400 °C for 8 h in air using an electric furnace (Crystal Systems, BF-1800-IV-II), and the acquired rods were used for crystallization. During the crystallization, the pull-down speed was 10 mm/h, and the upper and lower rotation rates were 23 rpm to the right and 20 rpm to the left, respectively. The synthesized samples were split, and a grinder polisher (Buehler, MetaServ 250) was used to mechanically polish the surfaces.

A diffractometer (Rigaku, MiniFlex600) equipped with a $\text{Cu K}\alpha$ micro-X-ray tube containing a Be window was used to measure the powder X-ray diffraction (XRD) patterns of the samples in the range of $2\theta = 10\text{--}70^\circ$. Diffuse transmission spectra were measured using a spectrophotometer (Shimadzu, Solidspec-3700).

Three-dimensional PL excitation and emission spectra and quantum yield (QY) were measured using Quantaaurus-QY (Hamamatsu Photonics, C11347). The measurement ranges of emission and excitation wavelengths were 300–800 nm and 250–400 nm, respectively. Quantaaurus- τ (Hamamatsu Photonics, C11367) was used to evaluate PL decay time profiles. X-ray-induced scintillation spectra were measured using our original setup.⁽³⁹⁾ The X-ray-induced scintillation decay and afterglow curves were evaluated using our original measurement system.⁽⁴⁰⁾

3. Results and Discussion

Figure 1 shows a photograph of the 0.01, 0.05, 0.1, 0.5, and 1.0% $\text{Eu}:\text{CaHfO}_3$ single crystals. All the samples looked colorless and transparent. Additionally, the length, width, and thickness of the 0.01, 0.05, 0.1, 0.5, and 1.0% $\text{Eu}:\text{CaHfO}_3$ were approximately $4 \times 4 \times 0.75 \text{ mm}^3$. Figure 2

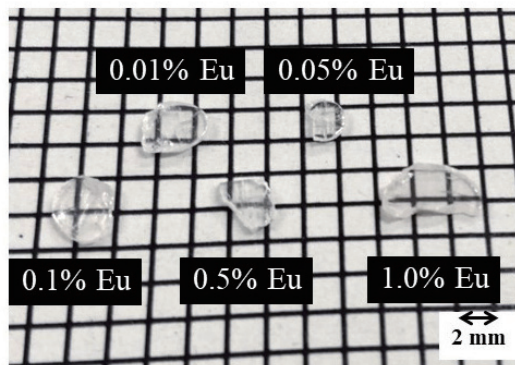


Fig. 1. (Color online) Photograph of Eu:CaHfO₃ single crystals.

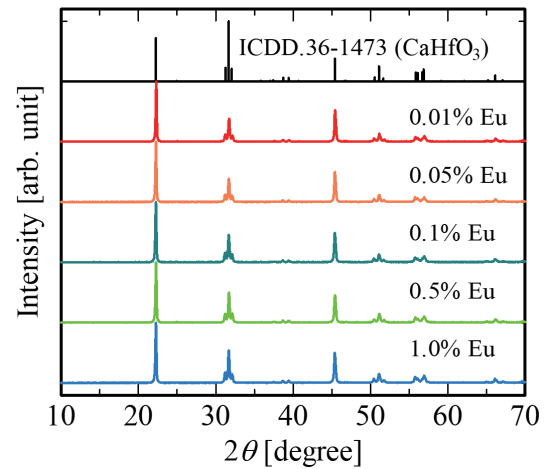


Fig. 2. (Color online) Powder XRD patterns of Eu:CaHfO₃ single crystals and reference data.

shows the powder XRD patterns of the Eu:CaHfO₃ single crystals and the reference data from International Crystallographic Diffraction Data (ICDD) No. 36-1473. The diffraction peaks of the samples were observed at the same positions as those of the reference data, and no impurity phases were detected. Hence, the synthesized samples had a single-phase structure of CaHfO₃.^(41,42)

Figure 3 shows the diffuse transmission spectra of Eu:CaHfO₃ in the wavelength range of 200 to 850 nm. In the 300–850 nm range, Eu:CaHfO₃ showed the maximum transmittance at approximately 70–80%, and the transmittances of the 0.05 and 0.5% doped samples were slightly lower than those of the other samples. The decrease in the transmittance arose from the presence of cracks, as shown in Fig. 1. Absorption attributed to the charge transfer of Eu³⁺–O²⁻ was observed in all the samples at wavelengths shorter than 300 nm.⁽⁴³⁾

Figure 4 shows the three-dimensional PL excitation and emission spectrum of the 1.0% Eu:CaHfO₃ as a typical sample. This Eu:CaHfO₃ showed the three emission peaks at 590, 620, and 690 nm originating from the 4f–4f transitions of Eu³⁺.^(44,45) A similar trend was observed in other samples. The PL *QY*s in the range of 550–750 nm under the 300 nm excitation wavelength of 0.01, 0.05, 0.1, 0.5, and 1.0% Eu:CaHfO₃ were 1.5, 4.6, 12.2, 32.6, and 42.2%, respectively. The increase in PL *QY* is attributed to an increase in Eu concentration, and no concentration quenching was observed in 0.01, 0.05, 0.1, 0.5, and 1.0% Eu:CaHfO₃.

Figure 5 shows the PL decay time profiles of 0.01, 0.05, 0.1, 0.5, and 1.0% Eu:CaHfO₃ single crystals, where the dashed lines indicate the fitted curves. All the decay curves of the samples were well approximated by a single-exponential function. Each obtained PL decay time constant was 0.96–0.99 ms, which was the range of typical values of the Eu³⁺-doped materials.^(46,47) Hence, the emission of the samples originated from the 4f–4f transitions of Eu³⁺.

Figure 6 shows the X-ray-induced scintillation spectra of Eu:CaHfO₃. All the Eu:CaHfO₃ samples showed several emission peaks at 420 nm (⁵D₃–⁷F₁), 430 nm (⁵D₃–⁷F₂), 450 nm (⁵D₃–

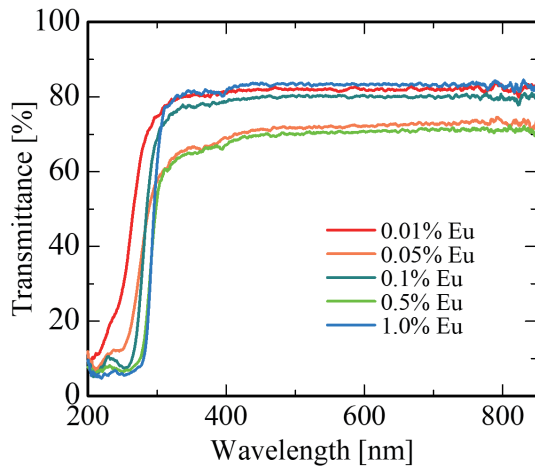


Fig. 3. (Color online) Diffuse transmission spectra of Eu:CaHfO₃.

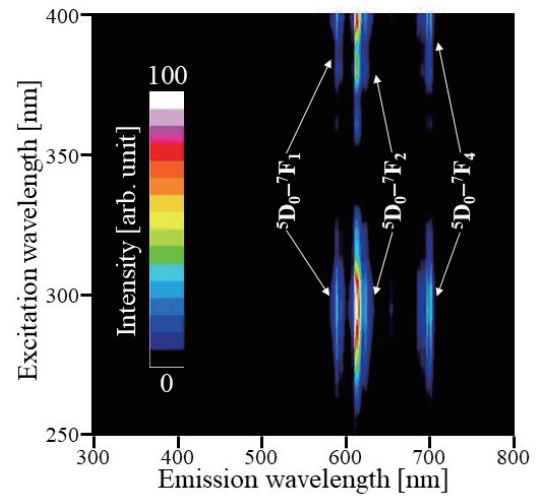


Fig. 4. (Color online) Three-dimensional PL excitation and emission spectrum of 1.0% Eu:CaHfO₃.

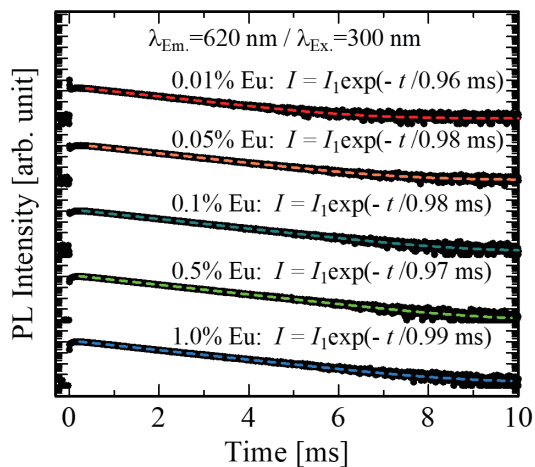


Fig. 5. (Color online) PL decay curves of Eu:CaHfO₃. The monitored and excitation wavelengths were 620 and 300 nm, respectively.

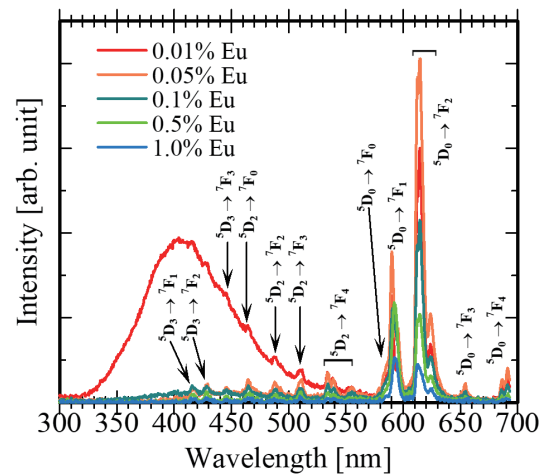


Fig. 6. (Color online) X-ray-induced scintillation spectra of Eu:CaHfO₃.

7F_3), 470 nm (${}^5D_2-{}^7F_0$), 490 nm (${}^5D_2-{}^7F_2$), 510 nm (${}^5D_2-{}^7F_3$), 530 nm (${}^5D_2-{}^7F_4$), 580 nm (${}^5D_0-{}^7F_0$), 590 nm (${}^5D_0-{}^7F_1$), 620 nm (${}^5D_0-{}^7F_2$), 650 nm (${}^5D_0-{}^7F_3$), and 690 nm (${}^5D_0-{}^7F_4$) owing to the 4f-4f transitions of Eu³⁺.^(33,35,36,48) In addition, the broad emission band at around 400 nm in 0.01% Eu:CaHfO₃ was derived from the host material.⁽²²⁻²⁵⁾ The highest intensity was observed in 0.05% Eu:CaHfO₃, and the trends in PL *QY* and the scintillation intensity were not consistent. Generally, the scintillation intensity depends on PL *QY* and the energy migration efficiency from the host to emission centers.⁽⁴⁹⁾ Therefore, the energy migration efficiency was more dominant than PL *QY* in affecting the scintillation properties of Eu:CaHfO₃.

Figure 7 shows the X-ray-induced scintillation decay time profiles of Eu:CaHfO₃, and the dashed lines show the fitted curves. The obtained decay curves of Eu:CaHfO₃ were approximated by a sum of two exponential components except for an instrumental response function (IRF). The first and second components, which were 0.80–1.1 ms and 2.8–3.0 ms, would be attributed to the host emission and the 4f–4f transitions of Eu³⁺,^(21,43,50,51) respectively.

Figure 8 shows the afterglow curves of Eu:CaHfO₃ samples. *AL* is defined as follows: AL [ppm] = $10^6 \times (I_2 - I_{bg}) / (I_1 - I_{bg})$, where I_{bg} , I_1 , and I_2 are the mean signal intensity in the background, with X-ray irradiation, and at $t = 20$ ms after irradiation, respectively. The *AL* values of 0.01, 0.05, 0.1, 0.5, and 1.0% Eu:CaHfO₃ were 10000, 3800, 4100, 1100, and 1000 ppm with a typical error of 8%, respectively. The obtained values were comparable to those of CaHfO₃ crystals doped with other dopant ions.^(18,22–24,26) Since general commercial scintillators such as CdWO₄ and Bi₄Ge₃O₁₂ have an *AL* value of around 10 ppm,⁽⁴⁰⁾ the *AL* value of Eu:CaHfO₃ was quite high.

4. Conclusions

Eu:CaHfO₃ single crystals were synthesized by the FZ method, and their PL and scintillation properties were investigated. PL *QY* was the highest at 42.2% in 1.0% Eu:CaHfO₃ under the excitation and emission wavelengths of 300 and 550–750 nm, respectively. The value was higher than those of Ce- and Pr-doped CaHfO₃ (32.6% and 6.8%,^(18,24) respectively). The scintillation spectra showed several emission peaks from 400 to 690 nm originating from the 4f–4f transitions of Eu³⁺. 0.05% Eu:CaHfO₃ showed the highest emission intensity among the present samples. 0.01% Eu:CaHfO₃ showed the lowest *AL* value of 1,000 ppm among the samples, and this value was higher than those of Ce- and Pr-doped CaHfO₃ (666 and 228 ppm,^(18,24) respectively). The results obtained in this study showed that the material properties of the Eu:CaHfO₃ single crystal were inadequate for practical use. On the other hand, previous studies showed that CaHfO₃ has excellent scintillation properties.^(21,26) Hence, the scintillation properties when using dopants other than Eu and the rare-earth elements considered in previous studies should be evaluated.

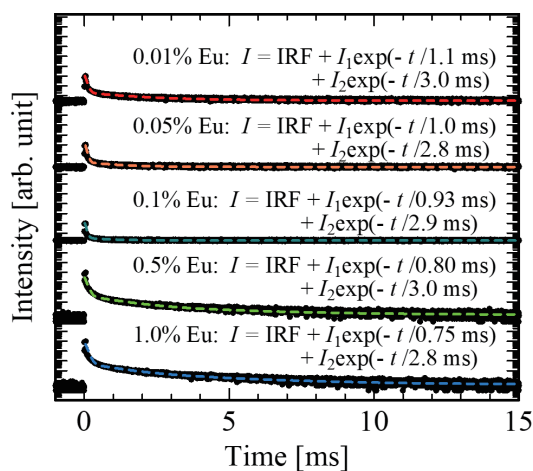


Fig. 7. (Color online) X-ray-induced scintillation decay time profiles of Eu:CaHfO₃.

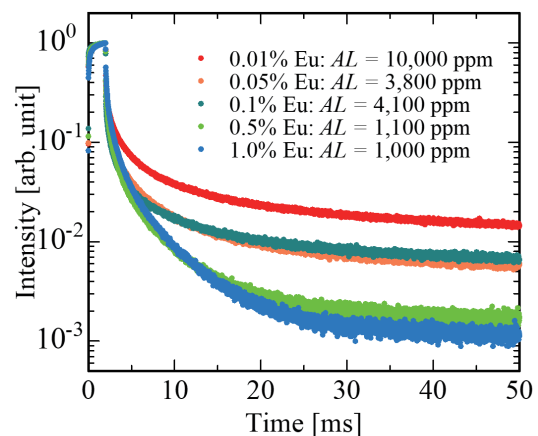


Fig. 8. (Color online) Afterglow curves of Eu:CaHfO₃ with 2 ms X-ray irradiation.

Acknowledgments

This work was supported by Grants-in-Aid for Scientific Research A (22H00309), Scientific Research B (22H03872, 22H02939, 21H03733, and 21H03736), Early-Career Scientists (23K13689), and Challenging Exploratory Research (22K18997) from the Japan Society for the Promotion of Science. The Cooperative Research Project of the Research Center for Biomedical Engineering, A-STEP from JST, Kazuchika Okura Memorial Foundation, Asahi Glass Foundation, Nakatani Foundation, and Konica Minolta Science and Technology Foundation are also acknowledged.

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